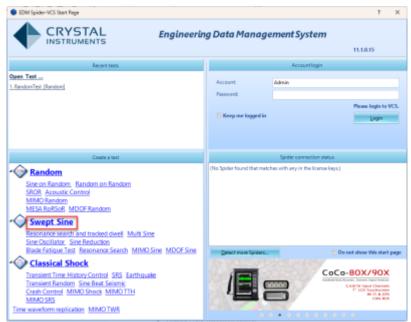
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# **VCS Swept Sine Testing**

## **Create New Test**

To create a new test, first open up EDM. On the VCS Start Page, select **Swept Sine** under the **Create a test** tab.



The New Test Wizard will now open up. From here, select Swept Sine again and then press Next.



Finally, give the test a name and select the Spider system that will be used to run the test. Once all is complete, press **Create**.

New Tell Wood ? X					
fill in the land: information for this text  Note you will be able to exactly for this text by "last names" or "last description".					
Country a new Surget Size text. Size/Feet					
Test same	Briefer		El Append the sequence number	1	
Test description					
Half description					
■ Use the default ideals of the previous test of the same type. If default ideals were not applied before the menufacturing settings will be used.					
Consterional by using a template.					
	,,				
Select Tem	plate name	Description			
Spider system	515,2597504	-			
Test directory:	CI/Sterl/Drevid	Documents/(EOth), demoi/GineTest	Choose		
If Create ness run failer for each run					
				- Sant Create test Canad	
				THE DIRECT CASE	

## **Test Configuration**

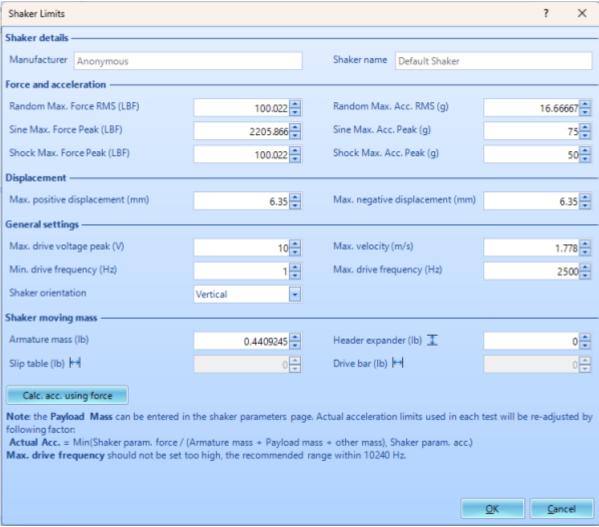
The test will now need to be configured to run. This includes inputting information regarding the shaker, creating the schedule for the test to follow, and determining the parameters for the frequency analysis. To access the **Test Configuration** menu, press the **Config** button that can be found on the right side of the screen.



#### **Shaker Parameters**

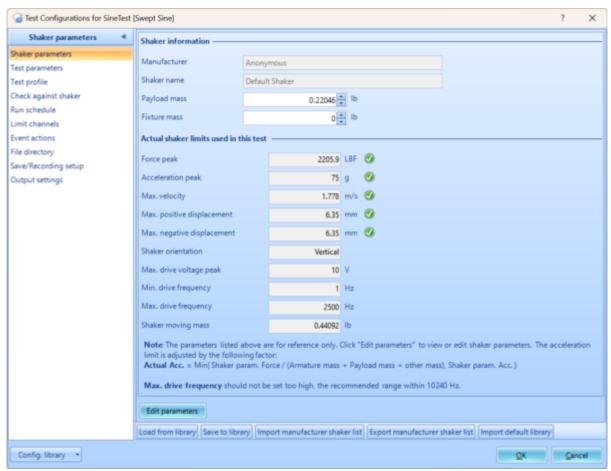
Click on **Edit Parameters** and enter the information from the shaker specifications. This is important for the safety of the shaker and testing unit.

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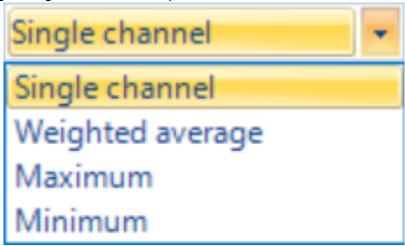


#### **Test Parameters**

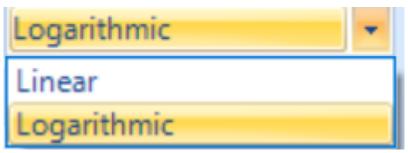
The **Test parameters** section in the **Test Configuration** window has settings for the analysis parameters, abort sensitivities and control strategy.



Control Strategy: Determines whether one or multiple control channels are used, and how the composite control signal is generated (if multiple channels are used).

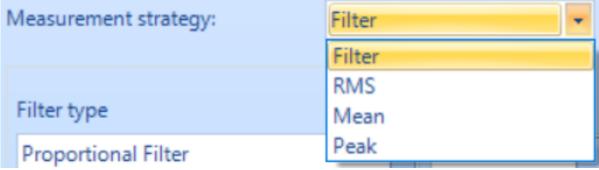


Sweep Type:



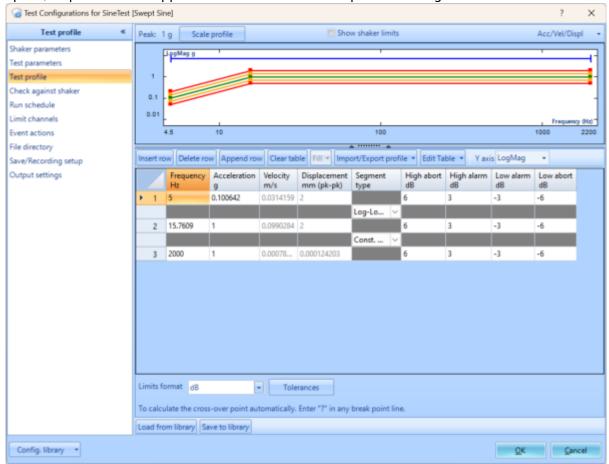
Measurement Strategy:

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#### **Test Profile**

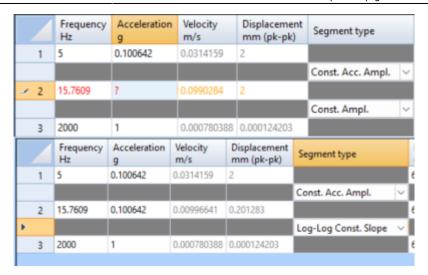
The test profile is defined in the Test Profile section of the Test Configuration window. A graphical preview of the profile plot is displayed above, with a breakpoint table below for entering the profile. CSV import / export is also supported as an alternative to profile editing.



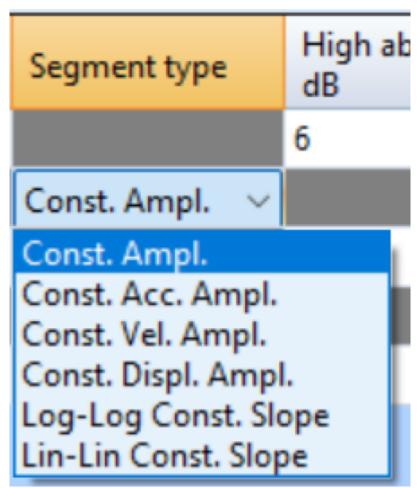
Breakpoint Table: Breakpoints can be added via **Insert row**, **Delete row** and **Append row**. Use **Clear table** to clear out all rows except for the first and last row.



Breakpoint Calculation: In the profile editor, EDM can calculate the crossover point given a specified slope and point value. If a '?' is entered as a Frequency or Amplitude value, EDM will interpolate that value given the slope before and after that point.

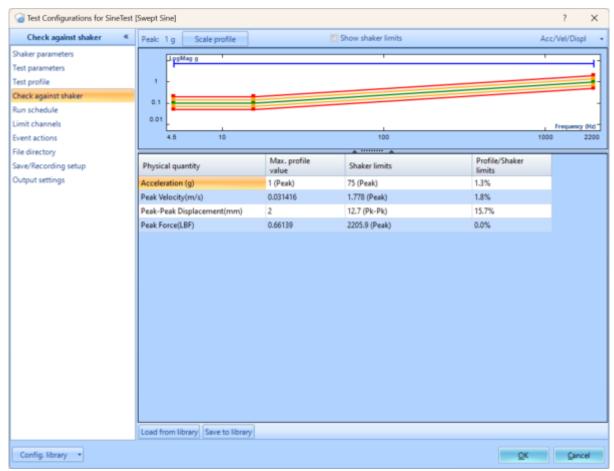


## Segment Type::

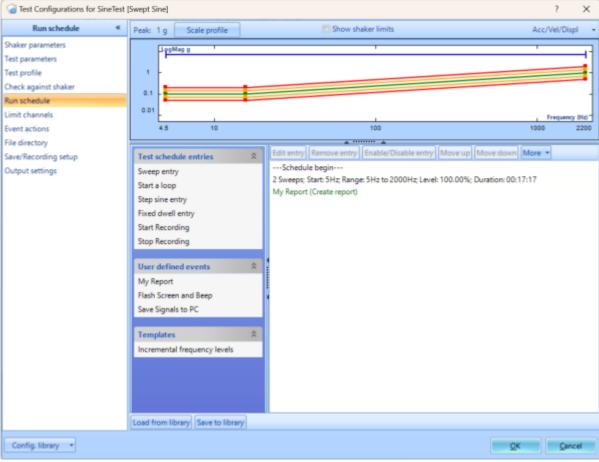


**Check Against Shaker** 

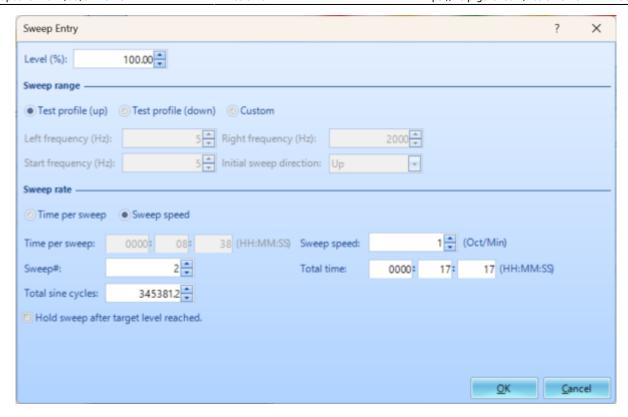
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#### **Run Schedule**

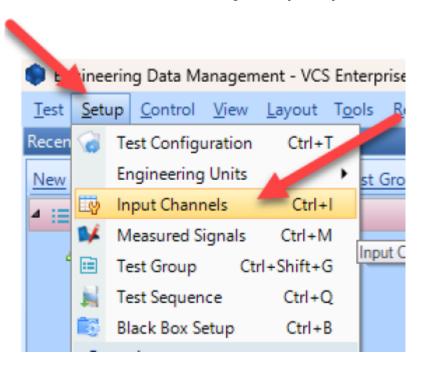


Sweep Entry:



# **Input Channels**

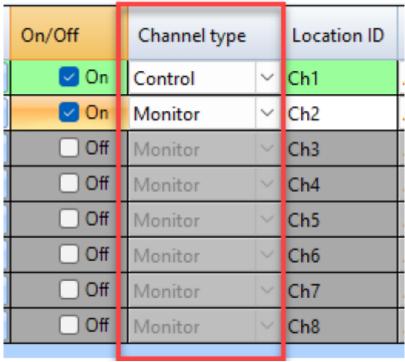
The input channels will now need to be set up. All sensors will to be properly configured before testing. The **Input Channels** menu can be found through **Setup** → **Input Channels**.



#### **Channel Type**

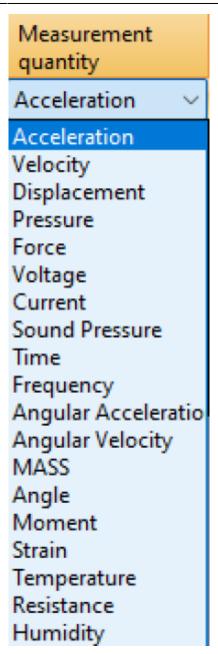
**Control** vs. **Monitor**. When running a test, there will need to be at least one control sensor. The control sensor is used to monitor the actual vibration levels that the shaker is producing. It then sends this data to the controller so that it maintains the targeted profile. This sensor should be mounted somewhere on the shaker/slip table itself, not the Device Under Test (DUT). Monitor sensors will show the levels that the DUT itself is experiencing.

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## **Measurement Quantity**

Defines the physical unit that will be measured by the sensor connected to the channel.



### Sensitivity

Sets the proportionality factor for the measurement (millivolts per engineering unit) given as a parameter of the sensor.\\Input Mode

There are five modes in which the inputs can operate:

*DC-Differential-* In the DC-Differential mode, neither of the input connections is referenced to the local ground. The input is taken as the potential difference between the two input terminals, and any potential in common with both terminals is canceled out. The Common Mode Voltage (CMV) will be rejected as long as the overall input voltage level does not saturate the input gain stage. Beware that very high CMV will cause clipping and may damage the input circuitry. Signals with a nonzero mean (DC component) can be measured in this mode.

*DC-Single End-* In single-ended mode, one of the input terminals is grounded and the input is taken as the potential difference of the center terminal with respect to this ground. Use this mode when the input needs to be grounded to reduce EMI noise or static buildup. Do not use this mode when the signal source is ground referenced or ground loop interference may result. This mode also allows signals with a non-zero mean to be measured.

AC-Differential- AC-Differential is a differential input mode that applies a low-frequency high-pass (DC-

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blocking) analog filter to the input. It rejects common mode signals and DC components in the input signal. Use this when DC and low-frequency AC voltage measurements are not required or when a DC bias voltage is present. The analog high-pass filter has a cutoff frequency of -3dB at 0.3 Hz, and -0.1dB at 0.7 Hz for the IEPE input mode.

AC-Single End- AC-Single End grounds one of the input terminals and enables the DC-blocking analog filter. Use this mode for non-ground referenced sources where measuring the DC or low-frequency components are not required. It shares the same high-pass filter as that of AC-Differential.

*IEPE (ICP)*- All Crystal Instruments products support IEPE (Integral Electronic PiezoElectric) constant current output type input channels. IEPE refers to a class of transducers that are packaged with built-in voltage amplifiers powered by a constant current. These circuits are powered by a 4 mA constant current source at roughly 21 Volts.

Charge- Some sensors provide a high-impedance charge output. Usually, these are high-sensitivity piezoelectric units that lack a built-in voltage mode amplifier (i.e. IEPE), allowing them to be used in high-temperature environments. The Spider-81 front-end module has a built-in charge amplifier that allows the system to read the output of these sensors

Sensitivity	Input mode	
100 (mV/g)	IEPE ~	
100 (mV/g)	IEPE ~	
100 (mV/g)	IEPE AC-Single End DC-Single End AC-Differential DC-Differential In-Line Charge Converte External Charge Amplifi External Charge Amplifi AC-Single End	
100 (mV/g)		

# **Running the Test**

Now that all of the parameters for the test have been setup, the test is ready to run. Here are the final steps to start the test.

- 1. Press the **Connect** button to connect to the controller.
- 2. Press the Run button.
- 3. The **Spider Check List** will now appear. Here you can check the settings of the test and verify that all is set up properly. Press **Start** once this has been verified.
- 4. The Pre-Test will now begin. This will verify that the control loop is properly established and provide data that the control loop needs.
- 5. The test is now running

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